



PATENT

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Allan Rosencwaig et al.

Application No.: 09/629,407

Filed: August 1, 2000

For: MEASUREMENT OF THIN FILMS
AND BARRIER LAYERS ON
PATTERNED WAFERS WITH X-RAY
REFLECTOMETRY

Confirmation No.:

Group Art Unit: 2876

Examiner: H.K. Song

SUBMISSION OF FORMAL DRAWINGS

121 Spear Street, Suite 290
San Francisco, CA 94105
(415) 512-1312

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STALLMAN & POLLOCK LLP

Dated: 02/18/2003

By: Georgia K. Stith

Georgia K. Stith

Sir:

Enclosed are three (3) sheets of formal drawings for filing in the above-referenced
application.

Respectfully submitted,

STALLMAN & POLLOCK LLP

Dated: February 18, 2003

By: Brian J. Keating

Brian J. Keating
Reg. No. 39,520

Attorneys for Applicant(s)

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